	Input Data					Algorithm			Coverage										Evaluation									Application				
Publication	feature model	domain knowledge	code artifacts	test artifacts	product set	greedy	evolutionary	manual selection	feature-wise coverage	pair-wise coverage	3-wise coverage	4-wise coverage	5-wise coverage	6-wise coverage	t-wise coverage	statement coverage	block coverage	requirements coverage	no coverage guarantee	sampling efficiency	testing efficiency	effectiveness	no tool	tool unavailable	available tool	open-source tool	evaluation	no evaluation	testing	type checking	data-flow analysis	non-functional properties
[1] [3] [4] [5] [6] [7] [8] [9] [11] [14] [12] [13] [15] [16] [17] [18] [19] [24] [25] [26] [27] [28] [30] [31] [33] [34] [36] [37] [38] [39] [40] [40] [41] [42] [57] [58] [58] [58] [58] [23] [55] [21] [46] [49] [20] [52] [55] [51] [52] [55] [50] [53] [59] [51] [32] [51]																																

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